

IN THE SPECIFICATION

Please amend the portions of the Specification identified below to read as indicated herein.

Paragraph starting at page 9, line 16:

B1
For testing the DUT 10, the ATE 200 having a tester-per-pin architecture comprises a plurality of individual per-pin testing units (not shown in detail in Fig. 2), each allowing to provide a stimulus signal to a specific pin of the DUT 10 and to receive a stimulus response therefrom. For testing the internal DUT-cores 15 (i.e. units 40, 50, and 20) of the DUT 10, the ATE 200 assigns an ATE-port 210 as a specific subset of individual per-pin testing units for testing the functionality of the internal DUT-cores 40, 50, and 20. Accordingly, the ATE 200 further provides an ATE-port 220 for testing the USB 110, an ATE-port-~~220~~ 230 for testing the DRAM 100, and an ATE-port-~~230~~ 240, for testing the LAN 70, each ATE-port having a specific subset of individual per-pin testing units.

Paragraph starting at page 10, line 6:

B2
Fig. 3 shows - from a different angle than Fig. 2 - the DUT 10 with examples of ATE-port assignments to pins of the DUT 10. In this example, the DUT 10 comprises individual DUT-pins 300A, 300B, ..., 300R, each DUT-pin representing an external electrical contact which can be accessed by an individual per-pin testing unit. For a first testing sequence, the DUT-pins 300A to 300E are assigned to an ATE-port A, the DUT-pins 300F to 300H are assigned to an ATE-port B, and the DUT-pins 300K to 300Q are assigned to an ATE-port D. In a next testing sequence, the ATE-ports 300B to 300H are assigned to an ATE-port C instead of the assignments A and B. While the ATE-ports A and B ~~maybe~~ may be concurrently used for testing, the ATE-port C can only be used independently of ATE-ports A and B.

Paragraph segment starting at page 16, line 23:

B3 an access control logic-~~850~~ 890 that supports e.g. broadcasting to a subset of per-pin testing units
(e.g. a subset constituting an ATE-port)

Paragraph starting at page 18, line 18:

B4 Besides storing the ATE-port definition and the name mappings in an appropriate data structure,
the invention configures the access control logic-~~850~~ 890 of the per-pin testing units 700i to be
able to store data or retrieve results by broadcasting.